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|                      | APPLICATION NO.  | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO. |
|----------------------|--|-------------|----------------------|---------------------|------------------|
|                      | 10/517,762   | 12/23/2004  | Hieu A. Lam          | 260280US6YAPCT      | 8443             |
|                      | 22850 7590 06/18/2007<br>OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C. |             |                      | EXAMINER            |                  |
|                      | 1940 DUKE STREET   |             |                      | KACKAR, RAM N       |                  |
| ALEXANDRIA, VA 22314 |  | A, VA 22314 | ,                    | ART UNIT            | PAPER NUMBER     |
|                      |  |             |                      | 1763                |                  |
|                      |  |             |                      |                     | <del>,</del>     |
|                      |  |             |                      | NOTIFICATION DATE   | DELIVERY MODE    |
|                      |  |             |                      | 06/18/2007          | ELECTRONIC       |

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

patentdocket@oblon.com oblonpat@oblon.com jgardner@oblon.com

|  | Application No.   | Applicant(s)          |  |  |  |  |
|--|---|-----------------------|--|--|--|--|
| Office Action Occurrence   | 10/517,762  | LAM ET AL.            |  |  |  |  |
| Office Action Summary  | Examiner  | Art Unit              |  |  |  |  |
|  | Ram N. Kackar   | 1763                  |  |  |  |  |
| The MAILING DATE of this communication app Period for Reply  | ears on the cover sheet with the c  | orrespondence address |  |  |  |  |
| A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.  - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b). |   |                       |  |  |  |  |
| Status   | ,   |                       |  |  |  |  |
| Responsive to communication(s) filed on <u>26 April 2007</u> .  This action is <b>FINAL</b> . 2b) This action is non-final.  Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.   |   |                       |  |  |  |  |
| Disposition of Claims  |   |                       |  |  |  |  |
| 4) Claim(s) 1-36 is/are pending in the application.  4a) Of the above claim(s) 12-36 is/are withdrawn from consideration.  5) Claim(s) is/are allowed.  6) Claim(s) 1-11 is/are rejected.  7) Claim(s) is/are objected to.  8) Claim(s) are subject to restriction and/or election requirement.  |   |                       |  |  |  |  |
| <ul> <li>9) The specification is objected to by the Examiner.</li> <li>10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.  Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).</li> <li>11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.</li> </ul>  |   |                       |  |  |  |  |
| Priority under 35 U.S.C. § 119   |   |                       |  |  |  |  |
| <ul> <li>12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some * c) None of:</li> <li>1. Certified copies of the priority documents have been received.</li> <li>2. Certified copies of the priority documents have been received in Application No.</li> <li>3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul>   |   |                       |  |  |  |  |
| • .  |   |                       |  |  |  |  |
| Attachment(s)  | _   |                       |  |  |  |  |
| Notice of References Cited (PTO-892)  Notice of Draftsperson's Patent Drawing Review (PTO-948)  Information Disclosure Statement(s) (PTO/SB/08)  Paper No(s)/Mail Date 12/2304.  | 4) Interview Summary ( Paper No(s)/Mail Da 5) Notice of Informal Pa 6) Other: | te                    |  |  |  |  |

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## **DETAILED ACTION**

#### Election/Restrictions

1. Applicant's election with traverse of claims 1-11 in the reply filed on 4/26/2007 is acknowledged. The traversal is on the ground(s) that there would not be a serious burden on the Examiner. This is not found persuasive because of large number of claims spread across different inventions.

The requirement is still deemed proper and is therefore made FINAL.

# Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 3. Claims 1-3, 5-8, 10-11 are rejected under 35 U.S.C. 102(b) as anticipated by or, in the alternative, under 35 U.S.C. 103(a) as obvious over Kosugi et al (US 6197116).

Makoto Kosugi disclose in situ monitoring of electrical parameters like impedance, phase, high frequency current and voltage (Abstract) while doing a plasma processing like etching on substrates of semiconductor. Makoto Kasugi discloses model for predicting processing characteristics like etch rate which determines etch depth, etch endpoint and

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processed profile (Col 1 line 66- Col 2 line 2) a diagnostics unit to diagnose condition of plasma and find fault and alarm situations. The processing characteristics could be etch rate. (See all document and specially abstract, Col 1 lines 59- Col 2 line2, Col 3 lines 24-34, Col 6 lines 18-56, Col 7 lines 42-55).

4. Claims 1-11 are rejected under 35 U.S.C. 102(e) as anticipated by or, in the alternative, under 35 U.S.C. 103(a) as obvious over Tanaka et al (US 6616759).

Tanaka et al disclose in situ monitoring of processing parameters like pressure, temperature, gas flow, impedance, current and voltage (Col 3 lines 52-60) while doing a plasma processing like etching on substrates of semiconductor. Tanaka et al disclose model for predicting processing characteristics, a diagnostics unit to find fault and alarm situations (Col 6 line 67 – Col 7 line 3). The processing characteristics could be etch rate which determines etch depth and the model is developed using Partial Least Square method (Col 4 line 29-Col 6 line61).

5. Claims 1-3, 5-8, 10-11 are rejected under 35 U.S.C. 102(b) as anticipated by or, in the alternative, under 35 U.S.C. 103(a) as obvious over Sharad Saxena (US 5642296).

Sharad Saxena disclose in situ monitoring of processing parameters like power, pressure, gas flow (Abstract) while doing a plasma processing like etching on substrates of semiconductor. Sharad Saxena discloses model for predicting processing characteristics like etch rate (Fig 6), a diagnostics unit to diagnose condition of plasma and find fault and alarm situations (abstract and Col 3 line3 to Col 10 line 67).

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## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ram N. Kackar whose telephone number is 571 272 1436. The examiner can normally be reached on M-F 8:00 A.M to 5:P.M.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Parviz Hassanzadeh can be reached on 571 272 1435. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Nan-

Ram Kackar

Primary Examiner AU 1763